

Performing High-Speed Parameter Extractions On High-Power Devices Using the HP 4142B Modular DC Source/Monitor

Application Note 1216-1

1. Introduction

The HP 4142B has the widest source/measurement range in the industry, from 20fA to 10A and 40uV to 1000V. These ranges can be further expanded by combining multiple modules. In addition, the HP 4142B's extensive list of measurement modes like spot, pulsed spot, pulsed sweep, 2 channel pulsed spot and many others will allow you to make the most accurate measurements possible.

The HP 4142B's Program Memory and Module Selector will save you time by allowing you to automate your measurements and DUT connections. Using a HP controller can further increase your programming productivity and measurement throughput.

1-1. Program Memory

The HP 4142B can store and execute test sequences from its internal memory. This minimizes the HP-IB command transfer time thus decreasing your total test time. This saving can be significant when performing spot, pulsed spot and 2 channel spot measurements which are especially important when extracting DC parameters on power devices.

1-2. Module Selector

You will need to change the measurement configurations in order to extract and obtain the most accurate dc parameters on a power device. The Module Selector (HP 16087A or HP 16088B Opt. 300) enables you to change the measurement configuration via your test program, thus saving you time and minimizing the chance of making connection errors. The Module selector is typically used to switch a SMU, HCU or HVU to a given DUT terminal. Refer to figure 1.

By utilizing the HP 4142B's program memory and module selector you can extract all seven basis dc parameters in only 1.4 seconds. This is more than 10 times faster (comparison performed by HP) than a curve tracer.

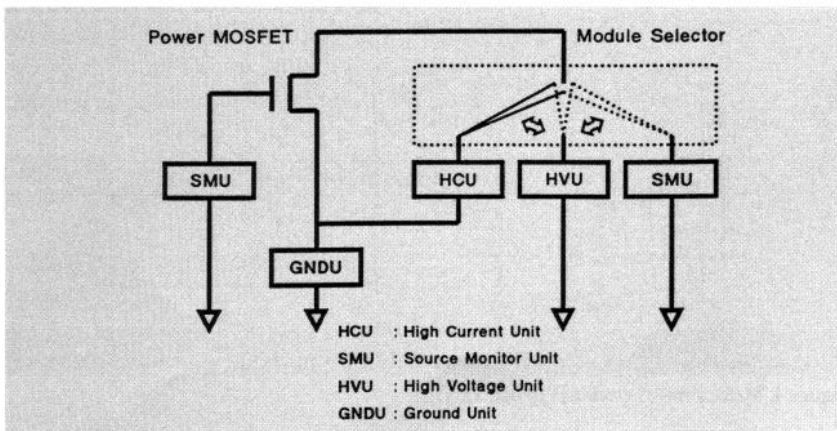


Figure 1. Automatically change measurement setups with the Module Selector

2. Measurement Parameters and Conditions

This section describes the seven measurement parameters.

2-1. Drain-Source ON State Voltage (V_{ds_on}) and Drain-Source ON State Resistance (R_{ds_on})

The drain-source On state voltage (V_{ds_on}) is measured when a specific gate voltage (V_{gs}) and drain current (I_d) are applied. The drain-source On resistance (R_{ds_on}) is equal to V_{ds_on}/I_d .

The V_{ds_on} measurement circuit is shown in figure 2.

2-2. Forward Transfer Admittance (Y_{fs})

The forward transfer admittance is defined as the device's ability to vary its drain current in response to gate-source voltage variations when the drain voltage is held constant.

Figure 3 graphically describes this measurement. Two different gate-source voltages V_{gs1} and V_{gs2} are applied and the resulting drain currents I_{ds1} and I_{ds2} are measured. The following equation is used to compute Y_{fs} .

$$Y_{fs} = (I_{ds2} - I_{ds1}) / (V_{gs2} - V_{gs1})$$

The Y_{fs} and V_{ds_on} measurement circuits are the same.

2-3. Gate Threshold Voltage (V_{th})

The gate threshold is defined as the gate voltage required to turn on the flow of drain current. The measurement is performed in the non-saturation region.

In order to minimize thermal generation affects which can corrupt your measurement results and decrease your measurement time, the HP 41425A Analog Feedback Unit (AFU) should be used.

The V_{th} measurement circuit is shown in figure 4.

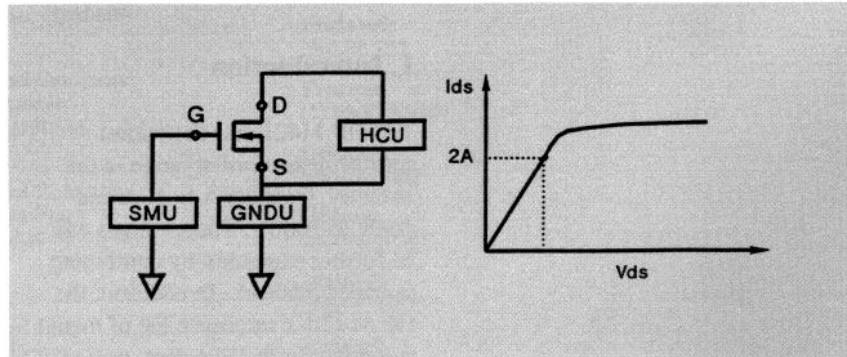


Figure 2. Measurement circuit (V_{ds_on} , R_{ds_on} and Y_{fs})

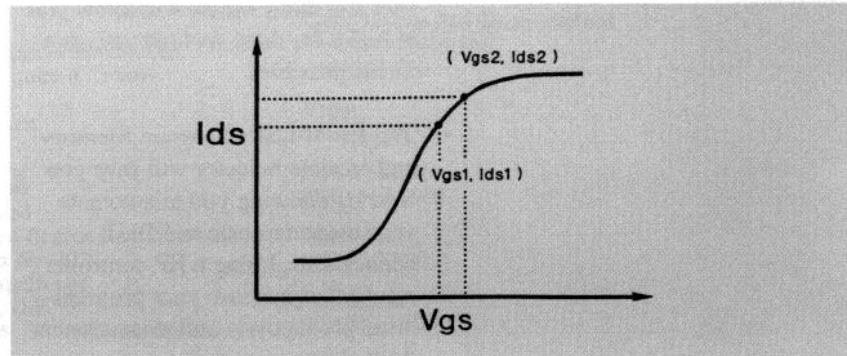


Figure 3. V_{gs} - I_{ds} characteristics

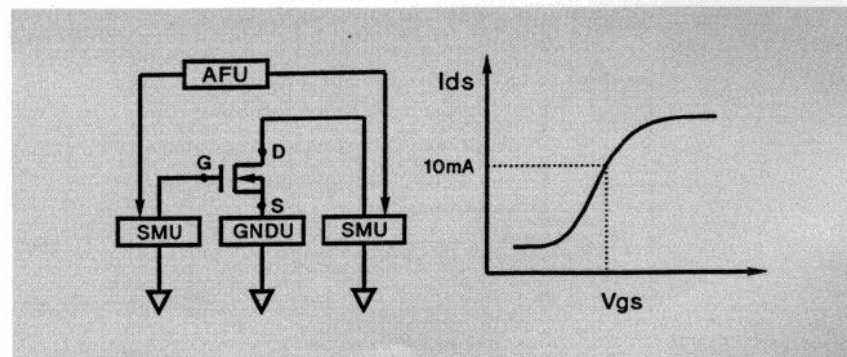


Figure 4. Measurement circuit (V_{th} and I_{gss})

2-4. Gate Leakage Current (I_{gss})

The gate leakage current is defined as the gate to source current when the drain and source are shorted and a specific gate voltage (V_{gs}) is applied.

The I_{gss} measurement circuit is shown in figure 4. The drain and source are effectively shorted together by programming the drain SMU to zero volts. The GNDU continuously outputs zero volts.

2-5. Drain Cut-Off Current (I_{dss})

The drain cut-off current is defined as the drain to source current when the gate and source are shorted and a specific drain voltage (V_d) is applied.

The I_{dss} measurement circuit is shown in figure 5. The gate and source are effectively shorted together by programming the gate SMU to zero volts. The GNDU continuously outputs zero volts.

2-6. Drain-Source Breakdown Voltage (B_{vdss})

The HP 4142B's quasi-pulse measurement mode* is superior to conventional force current/monitor voltage measurement methods. This special measurement mode minimizes thermal drift and device stress thus improving measurement quality and accuracy. It can also significantly improve your measurement time.

The B_{vdss} measurement circuit is shown in figure 5.

*Quasi-pulse measurement mode summary

The measurement sequence is:

- 1) Force current as specified by the current compliance.
- 2) Monitor the voltage and calculate the voltage slew rate.
- 3) When the Device Under Test (DUT) starts to enter breakdown, the voltage slew rate will decrease. At this time the SMU waits the user-specified delay time and measures the output voltage.
- 4) After the voltage measurement has been completed, the output voltage is quickly returned to the start voltage.

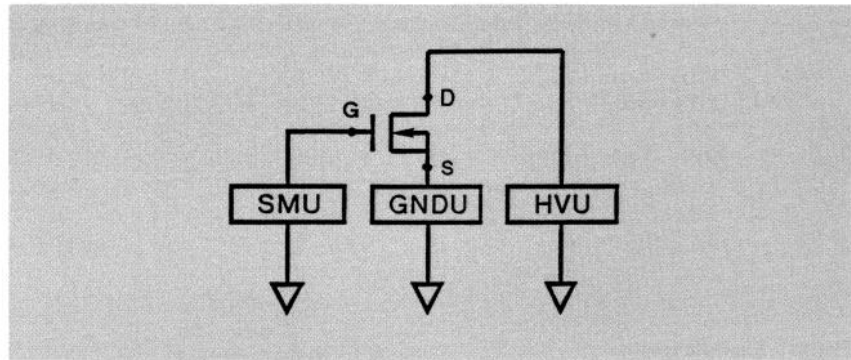


Figure 5. Measurement circuit (I_{dss} and B_{vdss})

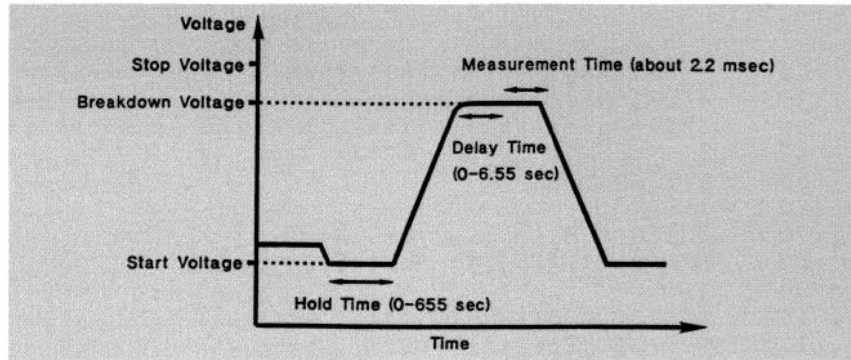


Figure 6. Quasi-pulse measurement mode voltage waveform

3. Measurement Results

Example measurement results are shown in figure 7. These were obtained in only 1.4 seconds. The tests are those described in Section 2 and the program used to derive these results in Section 4.

```
***** Parameter Measurement (Power MOSFET) *****
Vds(on)      = 4.724      (V)   (Id=2A,Vg=15V)   [HCU]
Rds(on)      = 2.362      (Ohm) (Id=2A,Vg=15V)  [HCU]
Yfs          = .699       (S)   (Vd=10V)        [HCU]
Vth (by AFU) = 3.904      (V)   (Vd=10V,Id=10mA) [MPSMU]
Igss         = 1.57E-10   (A)   (Vg=20V)        [MPSMU]
Idss         = 8.82E-9    (A)   (Vd=320V)       [HVU]
Bvdss       = 493.9      (V)   (Id=10uA)       [HVU]
```

Figure 7. Example results

4. Measurement Program

```
10  !*****
20  ! High speed measurement using program memory and module selector
30  !*****
40  !
50  OPTION BASE 1
60  !
70  INTEGER Hpsmu,Smu,Hcu,Hvu
80  DIM A$(7)[15],Vg_no2(2),Id_no2(2)
90  !
100 ASSIGN @Hp4142 TO 724
110 OUTPUT @Hp4142;"*RST"
120 Hpsmu=2
130 Smu=3
140 Hcu=5
150 Hvu=7
160 !
170 !*****
180 ! Parameter settings
190 !*****
200 !-----#1 Parameter settings [HCU]-----
210 ! Vds_on,Rds_on measurement
220 !
230 Vg_on=15      ! Vg=15V
240 Igcomp_no1=.1 ! Igcomp=100mA
250 Id_on=2       ! Id=2A
260 Vdcomp_no1=10 ! Vdcomp=10V
270 P_width=1.E-4 ! P_width=0.1ms
```

```

280 P_cycle=1.E-2          ! P_cycle=10ms
290 !
300 !-----#2 Parameter settings [HCU]-----
310 !           Yfs measurement
320 !
330 Vd_no2=10             ! Vd=10V
340 P_width_no2=1.E-4    ! P_width=100us
350 Vg_no2(1)=5.5        ! Vg_point1=5.5V
360 Vg_no2(2)=6.0        ! Vg_point2=6.0V
370 Idcomp_no2=5         ! Idcomp=5A
380 Igcomp_no2=.1        ! Igcomp=100mA
390 !
400 !-----#3 Parameter settings [SMU]-----
410 !           Igss measurement
420 !
430 Vg_no3=20             ! Vg=20V
440 Igcomp_no3=1.E-4     ! Igcomp=100uA
450 Vd_no3=0             ! Vd=0V
460 Idcomp_no3=1.E-1    ! Idcomp=100mA
470 !
480 !-----#4 Parameter settings [SMU]-----
490 !           Vth_afu measurement
500 !
510 Vg_start_no4=3       ! Vg_start=3V
520 Vg_stop_no4=4        ! Vg_stop=4V
530 Vg_rate_no4=5000    ! Vg_rate=5000
540 Igcomp_no4=1.E-4    ! Igcomp=100us
550 Vd_no4=10            ! Vd=10V
560 Id_target=.01       ! Id_target=10mA
570 Idcomp_no4=.1       ! Idcomp=100mA
580 Integ_time=4.5E-4   ! Integ_time=450us
590 Delay_time=1.E-4    ! Delay_time=100us
600 !
610 !-----#5 Parameter settings [HVU]-----
620 !           Idss measurement
630 !
640 Vd_no5=320           ! Vd_no5=320V
650 Vg_no5=0             ! Vg_no5=0V
660 Idcomp_no5=1.E-5    ! Idcomp=10uA
670 Igcomp_no5=1.E-4    ! Igcomp=100uA
680 !
690 !-----#6 Parameter settings [HVU]-----
700 !           Bvdss measurement
710 !
720 Vg_no6=0             ! Vg=0V
730 Igcomp_no6=1.E-4    ! Igcomp=100uA
740 Hold_time_no6=0     ! Hold_time=0s
750 Delay_time_no6=0    ! Delay_time=0s
760 Vd_start_no6=450    ! Vd_start=450V
770 Vd_stop_no6=600     ! Vd_stop=600V
780 Idcomp_no6=1.00E-5  ! Id_comp=10uA
790 !
800 !*****
810 !           Program #1
820 !           Vds_on,Rds_on measurement using the HCU
830 !*****
840 !

```

```

850 OUTPUT @Hp4142;"ST";1
860 OUTPUT @Hp4142;"ERC";1,3
870 OUTPUT @Hp4142;"FL";0,Hpsmu
880 OUTPUT @Hp4142;"PDI";Hcu,21,0,Id_on,Vdcomp_no1
890 OUTPUT @Hp4142;"PT";0,P_width,P_cycle
900 OUTPUT @Hp4142;"PV";Hpsmu,12,0,Vg_on,Igcomp_no1
910 OUTPUT @Hp4142;"MM";7,Hcu
920 OUTPUT @Hp4142;"XE"
930 OUTPUT @Hp4142;"END"
940 !
950 !*****
960 !           Program #2
970 !           Yfs measurement using the HCU
980 !*****
990 !
1000 OUTPUT @Hp4142;"ST";2
1010 OUTPUT @Hp4142;"DV";Hpsmu,12,Vg_no2(1),Igcomp_no2
1020 OUTPUT @Hp4142;"PT";0,1.00E-4,1.0E-2
1030 OUTPUT @Hp4142;"PV";Hcu,12,0,Vd_no2,Idcomp_no2
1040 OUTPUT @Hp4142;"MM";3,Hcu
1050 OUTPUT @Hp4142;"XE"
1060 OUTPUT @Hp4142;"DV";Hpsmu,12,Vg_no2(2),Igcomp_no2
1070 OUTPUT @Hp4142;"PT";0,1.00E-4,1.0E-2
1080 OUTPUT @Hp4142;"PV";Hcu,0,0,Vd_no2,Idcomp_no2
1090 OUTPUT @Hp4142;"MM";3,Hcu
1100 OUTPUT @Hp4142;"XE"
1110 OUTPUT @Hp4142;"END"
1120 !
1130 !*****
1140 !           Program #3
1150 !           Igss measurement using the SMU
1160 !*****
1170 !
1180 OUTPUT @Hp4142;"ST";3
1190 OUTPUT @Hp4142;"ERC";1,1
1200 OUTPUT @Hp4142;"DV";Smu,12,Vd_no3,Idcomp_no3
1210 OUTPUT @Hp4142;"DV";Hpsmu,12,Vg_no3,Igcomp_no3
1220 OUTPUT @Hp4142;"MM";1,Hpsmu
1230 OUTPUT @Hp4142;"XE"
1240 OUTPUT @Hp4142;"END"
1250 !
1260 !*****
1270 !           Program #4
1280 !           Vth(by AFU) measurement using the SMU
1290 !*****
1300 !
1310 OUTPUT @Hp4142;"ST";4
1320 OUTPUT
@Hp4142;"ASV";Hpsmu,Vg_start_no4,Vg_stop_no4,Vg_rate_no4,Igcomp_no
1330 OUTPUT @Hp4142;"AVI";Smu,Vd_no4,Id_target,Idcomp_no4
1340 OUTPUT @Hp4142;"ASM";1,1,Integ_time
1350 OUTPUT @Hp4142;"AT";0,Delay_time
1360 OUTPUT @Hp4142;"MM";6
1370 OUTPUT @Hp4142;"XE"
1380 OUTPUT @Hp4142;"END"
1390 !

```

```

1400 !*****
1410 !           Program #5
1420 !           Idss measurement using the HVU
1430 !*****
1440 !
1450 OUTPUT @Hp4142;"ST";5
1460 OUTPUT @Hp4142;"ERC";1,2
1470 OUTPUT @Hp4142;"DV";Hpsmu,12,Vg_no5,Igcomp_no5
1480 OUTPUT @Hp4142;"DV";Hvu,17,Vd_no5,Idcomp_no5
1490 OUTPUT @Hp4142;"MM";1,Hvu
1500 OUTPUT @Hp4142;"XE"
1510 OUTPUT @Hp4142;"END"
1520 !
1530 !*****
1540 !           Program #6
1550 !           Bvdss measurement using the HVU
1560 !*****
1570 !
1580 OUTPUT @Hp4142;"ST";6
1590 OUTPUT @Hp4142;"POL";Hvu,0
1600 OUTPUT @Hp4142;"MM";9,Hvu
1610 OUTPUT @Hp4142;"DV";Hpsmu,12,Vg_no6,Igcomp_no6
1620 OUTPUT @Hp4142;"BDT";Hold_time_no6,Delay_time_no6
1630 OUTPUT @Hp4142;"BDM";1,0
1640 OUTPUT @Hp4142;"BDV";Hvu,17,Vd_start_no6,Vd_stop_no6,Idcomp_no6
1650 OUTPUT @Hp4142;"XE"
1660 OUTPUT @Hp4142;"END"
1670 !
1680 !*****
1690 !           Measure parameters
1700 !*****
1710 !
1720 !-----
1730 OUTPUT @Hp4142;"CN";Hpsmu,Smu,Hcu,Hvu      ! OUTPUT RELAY ON
1740 !-----
1750 !
1760 OUTPUT @Hp4142;"DO";1
1770 ENTER @Hp4142 USING "#,3A,12D,2X";A$(1),Vdson
1780 !
1790 OUTPUT @Hp4142;"DO";2
1800 ENTER @Hp4142 USING "#,3A,12D,2X";A$(6),Id_no2(1)
1810 ENTER @Hp4142 USING "#,3A,12D,2X";A$(7),Id_no2(2)
1820 !
1830 OUTPUT @Hp4142;"DO";3
1840 ENTER @Hp4142 USING "#,3A,12D,2X";A$(2),Igss
1850 !
1860 OUTPUT @Hp4142;"DO";4
1870 ENTER @Hp4142 USING "#,3A,12D,2X";A$(3),Vth_afu
1880 !
1890 OUTPUT @Hp4142;"DO";5
1900 ENTER @Hp4142 USING "#,3A,12D,2X";A$(4),Idss
1910 !
1920 OUTPUT @Hp4142;"DO";6
1930 ENTER @Hp4142 USING "#,3A,12D,2X";A$(5),Bvdss
1940 !

```

```

1950 !-----
1960 OUTPUT @Hp4142;"CL"                ! OUTPUT RELAY OFF
1970 !-----
1980 !
1990 !*****
2000 !                Parameter analysis
2010 !*****
2020 !
2030 !----Rds_on-----
2040 Rdson=Vdson/Id_on
2050 !
2060 !----Yfs (2 point method)-----
2070 Ccc=(Id_no2(2)-Id_no2(1))/(Vg_no2(2)-Vg_no2(1))
2080 Yfs=Ccc
2090 !
2100 !*****
2110 !                Print parameters
2120 !*****
2130 !
2140 PRINT USING "@"
2150 PRINT "***** Parameter Measurement (Power MOSFET)
*****"
2160 PRINT
2170 PRINT "Vds(on)          =",PROUND(Vdson,-3)," (V) (Id=2A,Vg=15V
[HCU]"
2180 PRINT "Rds(on)          =",PROUND(Rdson,-3)," (Ohm) (Id=2A,Vg=15V
[HCU]"
2190 PRINT "Yfs              =",PROUND(Yfs,-3)," (S) (Vd=10V)
[HCU]"
2200 PRINT "Vth (by AFU)      =",PROUND(Vth_afu,-3)," (V)
(Vd=10V,Id=10mA) [MPSMU]"
2210 PRINT "Igss             =",PROUND(Igss,-12);" (A) (Vg=20V)
[MPSMU]"
2220 PRINT "Idss             =",PROUND(Idss,-11);" (A) (Vd=320V)
[HVU]"
2230 PRINT "Bvdss           =",PROUND(Bvdss,-1)," (V) (Id=10uA)
[HVU]"
2240 KEY LABELS OFF
2250 !DUMP ALPHA #701
2260 KEY LABELS ON
2270 !
2280 END

```

Description

200-280 Defines the Vds_on measurement parameters.
300-380 Defines the Yfs measurement parameters.
400-460 Defines the Igss measurement parameters.
480-590 Defines the Vth measurement parameters.
610-670 Defines the Idss measurement parameters.
690-780 Defines the Bvdss measurement parameters.
800-930 Stores Vds_on measurement program in memory.
950-1110 Stores Yfs measurement program in memory.
1130-1240 Stores Igss measurement program in memory.
1260-1380 Stores Vth measurement program in memory.
1400-1510 Stores Idss measurement program in memory.
1530-1660 Stores Bvdss measurement program in memory.
1730 Sets the output relay to on.
1760-1930 Executes each program.
1960 Sets the output relay to off.
2030-2040 Calculates Rds_on.
2060-2080 Calculates Yfs.
2100-2230 Displays measurement results.

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